

RFP12N10L

Data Sheet

April 2005

12A, 100V, 0.200 Ohm, Logic Level, N-Channel Power MOSFET

These are N-Channel enhancement mode silicon gate power field effect transistors specifically designed for use with logic level (5V) driving sources in applications such as programmable controllers, automotive switching and solenoid drivers. This performance is accomplished through a special gate oxide design which provides full rated conduction at gate biases in the 3V to 5V range, thereby facilitating true on-off power control directly from logic circuit supply voltages.

Formerly developmental type TA09526.

Ordering Information

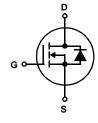
PART NUMBER	PACKAGE	BRAND
RFP12N10L	TO-220AB	F12N10L

NOTE: When ordering, include the entire part number.

Features

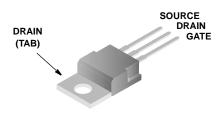
- 12A, 100V
- r_{DS(ON)} = 0.200Ω
- Design Optimized for 5V Gate Drives
- Can be Driven Directly from QMOS, NMOS, TTL Circuits
- · Compatible with Automotive Drive Requirements
- SOA is Power-Dissipation Limited
- Nanosecond Switching Speeds
- Linear Transfer Characteristics
- High Input Impedance
- Majority Carrier Device
- Related Literature
 - TB334 "Guidelines for Soldering Surface Mount Components to PC Boards

Symbol



Packaging

JEDEC TO-220AB



Absolute Maximum Ratings $T_{C} = 25^{\circ}C$, Unless Otherwise Specified

	RFP12N10L	UNITS
Drain to Source Voltage (Note 1)	100	V
Drain to Gate Voltage (R_{GS} = 1M Ω) (Note 1)	100	V
Continuous Drain Current I _D	12	А
Pulsed Drain Current (Note 3)	30	А
Gate to Source VoltageV _{GS}	±10	V
Maximum Power Dissipation	60	W
Above T _C = 25 ^o C, Derate Linearly	0.48	W/ ^o C
Operating and Storage Temperature	-55 to 150	oC
Maximum Temperature for Soldering Leads at 0.063in (1.6mm) from Case for 10sT _L Package Body for 10s, See Techbrief 334T _{pkg}	300 260	°C Oo

CAUTION: Stresses above those listed in "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.

NOTE:

1. $T_J = 25^{\circ}C$ to $125^{\circ}C$.

PARAMETER	SYMBOL	TEST CONDITIONS		MIN	TYP	MAX	UNITS
Drain to Source Breakdown Voltage	BV _{DSS}	I _D = 250μA, V _{GS} = 0V		100	-	-	V
Gate to Threshold Voltage	V _{GS(TH)}	$V_{GS} = V_{DS}$, $I_D = 250 \mu A$ (Figure 7)		1	-	2	V
Zero Gate Voltage Drain Current		V _{DS} = 80V		-	-	1	μΑ
	IDSS	$V_{GS} = 0V$	T _C = 125 ⁰ C	-	-	50	μΑ
Gate to Source Leakage Current	I _{GSS}	V _{GS} = 10V, V _{DS} = 0V		-	-	100	nA
Drain to Source On Resistance (Note 2)	^r DS(ON)	I _D = 12A, V _{GS} = 5V (Figures 5, 6)		-	-	0.200	Ω
Input Capacitance	C _{ISS}	V _{GS} = 0V, V _{DS} = 25V, f = 1MHz (Figure 8)		-	-	900	pF
Output Capacitance	C _{OSS}			-	-	325	pF
Reverse-Transfer Capacitance	C _{RSS}			-	-	170	pF
Turn-On Delay Time	t _{d(ON)}	$I_{D} = 6A, V_{DD} = 50V, R_{G} = 6.25\Omega, V_{GS} = 5V$ (Figures 9, 10, 11)		-	15	50	ns
Rise Time	t _r			-	70	150	ns
Turn-Off Delay Time	t _{d(OFF)}			-	100	130	ns
Fall Time	t _f			-	80	150	ns
Thermal Resistance Junction to Case	R _{θJC}	TO-220				2.083	oC/W

Source to Drain Diode Specifications

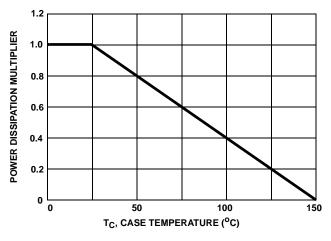
PARAMETER	SYMBOL	TEST CONDITIONS	MIN	ТҮР	MAX	UNITS
Source to Drain Diode Voltage (Note 2)	V _{SD}	I _{SD} = 6A	-	-	1.4	V
Diode Reverse Recovery Time	t _{rr}	I _{SD} = 4A, dI _{SD} /dt = 50A/μs	-	150	-	ns

NOTES:

2. Pulsed: pulse duration = $80\mu s$ max, duty cycle = 2%.

3. Repetitive rating: pulse width limited by maximum junction temperature.

Typical Performance Curves Unless Otherwise Specified





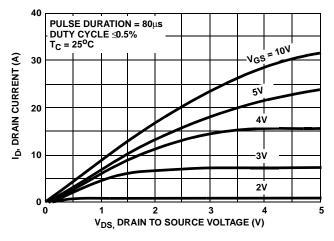


FIGURE 3. SATURATION CHARACTERISTICS

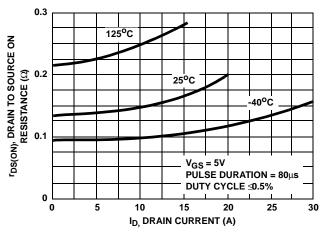


FIGURE 5. DRAIN TO SOURCE ON RESISTANCE vs DRAIN CURRENT

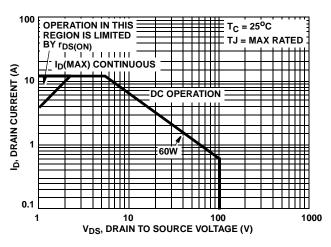
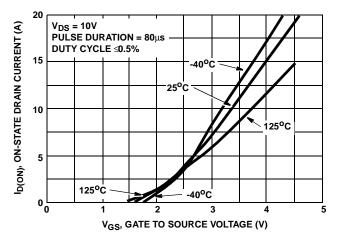


FIGURE 2. FORWARD BIAS OPERATING AREA





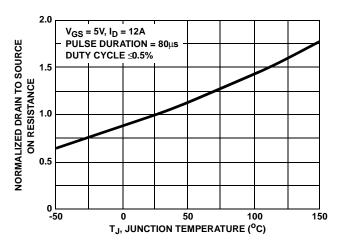
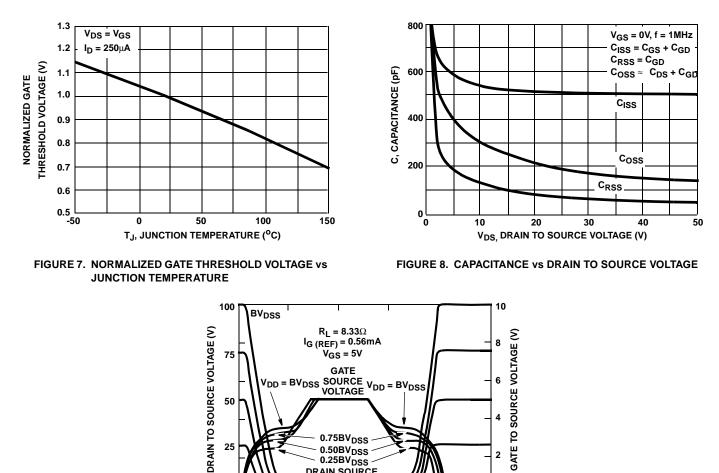


FIGURE 6. NORMALIZED DRAIN TO SOURCE ON RESISTANCE vs JUNCTION TEMPERATURE

Typical Performance Curves Unless Otherwise Specified (Continued)



NOTE: Refer to Fairchild Applications Notes AN7254 and AN7260 FIGURE 9. NORMALIZED SWITCHING WAVEFORMS FOR CONSTANT GATE CURRENT

t, TIME (µs)

BV_{DSS} SOURCE V_{DD} = BV_{DSS} VOLTAGE

0.75BV_{DSS}

0.50BV_{DSS}

0.25BV_{DSS} DRAIN SOURCE VOLTAGE

DD

I_G (REF)

IG (ACT)

20

50

25

0

Test Circuits and Waveforms

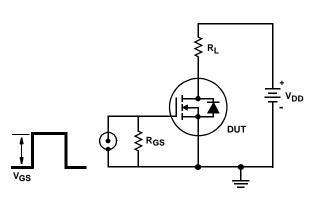
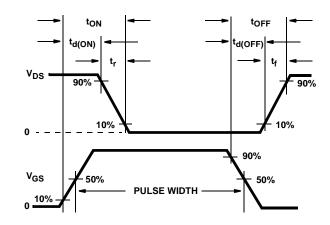


FIGURE 10. SWITCHING TIME TEST CIRCUIT



GATE -2

0

 $80 \frac{I_{G} (REF)}{I_{G} (ACT)}$

FIGURE 11. RESISTIVE SWITCHING WAVEFORMS

Test Circuits and Waveforms (Continued)

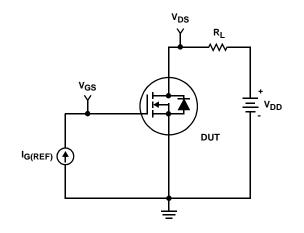


FIGURE 12. GATE CHARGE TEST CIRCUIT

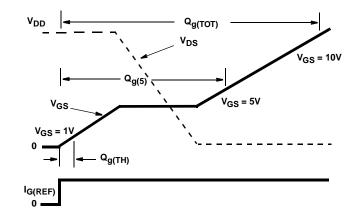


FIGURE 13. GATE CHARGE WAVEFORMS

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EnSigna™	<i>i-Lo</i> ™	MSXPro™	Quiet Series [™]	TINYOPTO™
FACT™	ImpliedDisconnect™	OCX™	RapidConfigure™	TruTranslation™
FACT Quiet Serie		OCXPro™	RapidConnect™	UHC™
Across the board	d. Around the world.™	OPTOLOGIC [®]	µSerDes™	UltraFET [®]
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